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1. Robust omniview-based probabilistic self-localization for mobile robots in large maze-like environments

Gross, H.-M.; Koenig, A.;
 Pattern Recognition, 2004. ICPR 2004. Proceedings of the 17th International Conference on Volume 3, 23-26 Aug. 2004 Page(s):266 - 269 Vol.3
 Digital Object Identifier 10.1109/ICPR.2004.1334518

[AbstractPlus](#) | Full Text: [PDF\(478 KB\)](#) IEEE CNF

2. Direct volume display devices

Clifton, T.E., III; Wefer, F.L.;
 Computer Graphics and Applications, IEEE Volume 13, Issue 4, July 1993 Page(s):57 - 65
 Digital Object Identifier 10.1109/38.219452

[AbstractPlus](#) | Full Text: [PDF\(632 KB\)](#) IEEE JNL

3. Process control and base line monitoring using optical 'On the Fly' and SEM classification as implemented in advanced DRAM manufacturing

Ralf, S.; Sina, P.; Dvori, S.; Bernhard, M.;
 Advanced Semiconductor Manufacturing Conference and Workshop, 2003 IEEE/SEMI 31 March-1 April 2003 Page(s):67 - 72

[AbstractPlus](#) | Full Text: [PDF\(498 KB\)](#) IEEE CNF

4. VHDL-based performance modeling: an application of the PMW tool suite to an image classification system

Ammon, J.; Hein, C.;
 VHDL International Users' Forum, 1997. Proceedings 19-22 Oct. 1997 Page(s):209 - 215
 Digital Object Identifier 10.1109/VIUF.1997.623952

[AbstractPlus](#) | Full Text: [PDF\(744 KB\)](#) IEEE CNF

5. Direct volumetric visualization

Williams, R.D.; Wefer, F.L.; Clifton, T.E., III;
 Visualization, 1992. Visualization '92, Proceedings., IEEE Conference on 19-23 Oct. 1992 Page(s):99 - 106
 Digital Object Identifier 10.1109/VISUAL.1992.235220

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6. Omnidvision-based probabilistic self-localization for a mobile shopping assistant continued

Gross, H.-M.; Koenig, A.; Schroeter, C.; Boehme, H.-J.;
 Intelligent Robots and Systems, 2003. (IROS 2003). Proceedings. 2003 IEEE/RSJ International Conference on

Volume 2, 27-31 Oct. 2003 Page(s):1505 - 1511 vol.2

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7. **Omniview cameras with curved surface mirrors**

Bruckstein, A.M.; Richardson, T.J.;
Omnidirectional Vision, 2000. Proceedings. IEEE Workshop on
12 June 2000 Page(s):79 - 84
Digital Object Identifier 10.1109/OMNVIS.2000.853809

[AbstractPlus](#) | Full Text: [PDF\(288 KB\)](#) IEEE CNF

8. **Hardware/software codesign of a scalable embedded radar signal processor**

Buenzli, C.; Owen, L.; Rose, F.;
VHDL International Users' Forum, 1997. Proceedings
19-22 Oct. 1997 Page(s):200 - 208
Digital Object Identifier 10.1109/VIUF.1997.623951

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9. **A novel human Interface of an omni-directional wheelchair**

Kamiuchi, S.; Maeysama, S.;
Robot and Human Interactive Communication, 2004. ROMAN 2004. 13th IEEE International
Workshop on
20-22 Sept. 2004 Page(s):101 - 106
Digital Object Identifier 10.1109/ROMAN.2004.1374737

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10. **A video pan/tilt/magnify/rotate system with no moving parts**

Zimmermann, S.; Kuban, D.;
Digital Avionics Systems Conference, 1992. Proceedings., IEEE/AIAA 11th
5-8 Oct. 1992 Page(s):523 - 531
Digital Object Identifier 10.1109/DASC.1992.282107

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END OF SEARCH HISTORY

Because these inventions are distinct for the reasons given above and have acquired a separate status in the art as shown by their different classification, restriction for examination purposes as indicated is proper.

Applicant is advised that the reply to this requirement to be complete must include an election of the invention to be examined even though the requirement be traversed (37 CFR 1.143).

Applicant is reminded that upon the cancellation of claims to a non-elected invention, the inventorship must be amended in compliance with 37 CFR 1.48(b) if one or more of the currently named inventors is no longer an inventor of at least one claim remaining in the application. Any amendment of inventorship must be accompanied by a request under 37 CFR 1.48(b) and by the fee required under 37 CFR 1.17(i).

Any inquiry concerning this communication or earlier communications from the examiner should be directed to S. Crane, whose telephone number is (571) 272-1652.

The supervisor for Art Unit 2811, Eddie Lee can be reached on (571) 272-1732. The fax phone number for the organization where this application or proceeding is assigned is (571) 273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see <http://pair-direct.uspto.gov>. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Application/Control Number: 10/827,326
Art Unit: 2811

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Art Unit 2811